

# 2SK2642-01MR

FUJI POWER MOS-FET

## N-CHANNEL SILICON POWER MOS-FET

### ■ Features

- High speed switching
- Low on-resistance
- No secondary breakdown
- Low driving power
- High voltage
- $V_{GS}=\pm 35V$  Guarantee
- Avalanche-proof

### ■ Applications

- Switching regulators
- UPS
- DC-DC converters
- General purpose power amplifier

### ■ Maximum ratings and characteristic Absolute maximum ratings

● ( $T_c=25^\circ C$  unless otherwise specified)

Item	Symbol	Rating	Unit
Drain-source voltage	$V_{DS}$	500	V
Continuous drain current	$I_D$	$\pm 15$	A
Pulsed drain current	$I_{D(puls)}$	$\pm 60$	A
Gate-source voltage	$V_{GS}$	$\pm 35$	V
Maximum Avalanche Energy	$E_{AV}^*1$	88.7	mJ
Max. power dissipation	$P_D$	50	W
Operating and storage temperature range	$T_{ch}$ $T_{stg}$	+150 -55 to +150	$^\circ C$ $^\circ C$

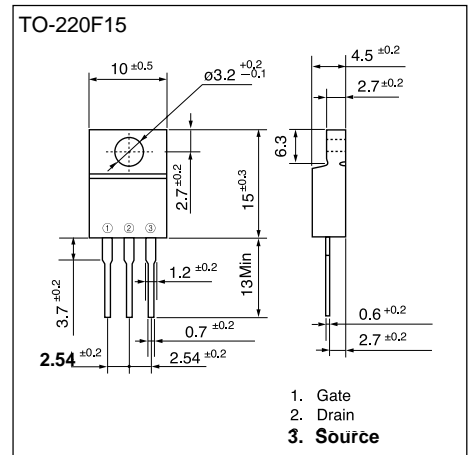
\*1  $L=0.72mH$ ,  $V_{cc}=50V$

### ● Electrical characteristics ( $T_c = 25^\circ C$ unless otherwise specified)

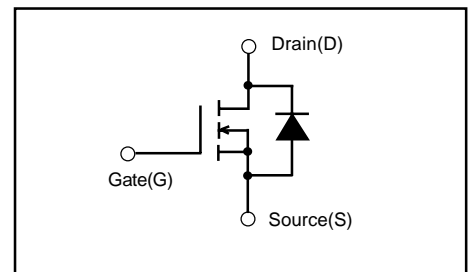
Item	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain-source breakdown voltage	$V_{(BR)DSS}$	$I_D=1mA$ $V_{GS}=0V$	500			V
Gate threshold voltage	$V_{GS(th)}$	$I_D=1mA$ $V_{DS}=V_{GS}$	3.5	4.0	4.5	V
Zero gate voltage drain current	$I_{DSS}$	$V_{DS}=500V$ $V_{GS}=0V$		10	500	$\mu A$
				0.2	1.0	mA
Gate-source leakage current	$I_{GSS}$	$V_{GS}=\pm 35V$ $V_{DS}=0V$		10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$I_D=7.5A$ $V_{GS}=10V$		0.44	0.55	$\Omega$
Forward transconductance	$g_{fs}$	$I_D=7.5A$ $V_{DS}=25V$	4.5	9.0		S
Input capacitance	$C_{iss}$	$V_{DS}=25V$		1400	2100	pF
Output capacitance	$C_{oss}$	$V_{GS}=0V$		250	380	
Reverse transfer capacitance	$C_{rss}$	$f=1MHz$		110	170	
Turn-on time $t_{on}$	$t_{d(on)}$	$V_{CC}=300V$ $I_D=15A$		30	50	ns
	$t_r$	$V_{GS}=10V$		110	170	
Turn-off time $t_{off}$	$t_{d(off)}$	$R_{GS}=10\Omega$		90	140	
	$t_f$			55	90	
Avalanche capability	$I_{AV}$	$L=100\mu H$ $T_{ch}=25^\circ C$	15			A
Diode forward on-voltage	$V_{SD}$	$I_F=2I_D$ $V_{GS}=0V$ $T_{ch}=25^\circ C$		1.1	1.65	V
Reverse recovery time	$t_{rr}$	$I_F=I_D$ $V_{GS}=0V$		500		ns
Reverse recovery charge	$Q_{rr}$	$-di/dt=100A/\mu s$ $T_{ch}=25^\circ C$		8.0		$\mu C$

### ● Thermal characteristics

Item	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal resistance	$R_{th(ch-c)}$	channel to case			2.50	$^\circ C/W$
	$R_{th(ch-a)}$	channel to ambient			62.5	$^\circ C/W$

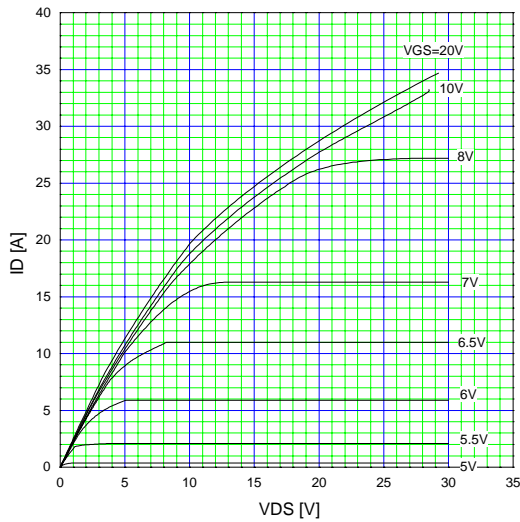


### ■ Equivalent circuit schematic

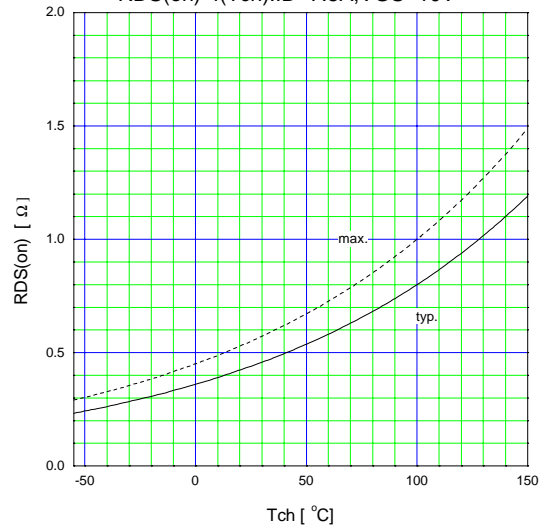


Characteristics

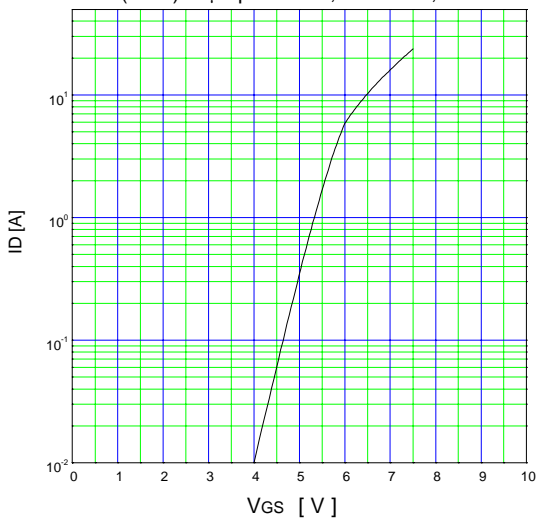
Typical output characteristics  
 $I_D=f(V_{DS})$ :80 $\mu$ s pulse test,  $T_c=25^\circ\text{C}$



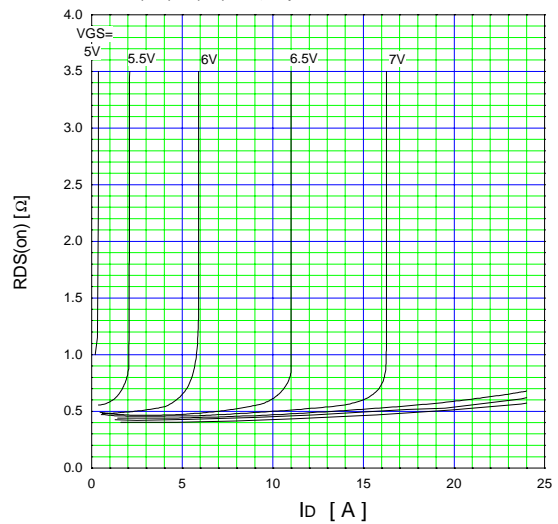
Drain-source on-state resistance  
 $R_{DS(on)}=f(T_{ch})$ : $I_D=7.5\text{A}$ ,  $V_{GS}=10\text{V}$



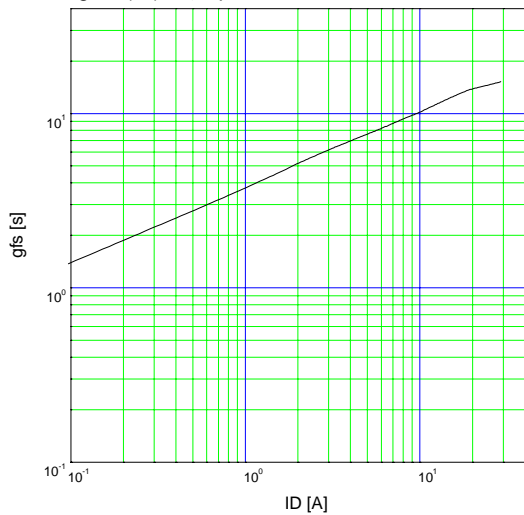
Typical transfer characteristic  
 $I_D=f(V_{GS})$ :80 $\mu$ s pulse test,  $V_{DS}=25\text{V}$ ,  $T_{ch}=25^\circ\text{C}$



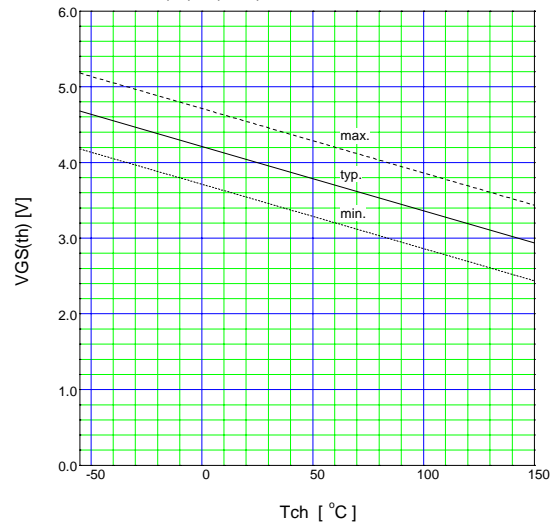
Typical drain-source on-state resistance  
 $R_{DS(on)}=f(I_D)$ :80 $\mu$ s pulse test,  $T_c=25^\circ\text{C}$



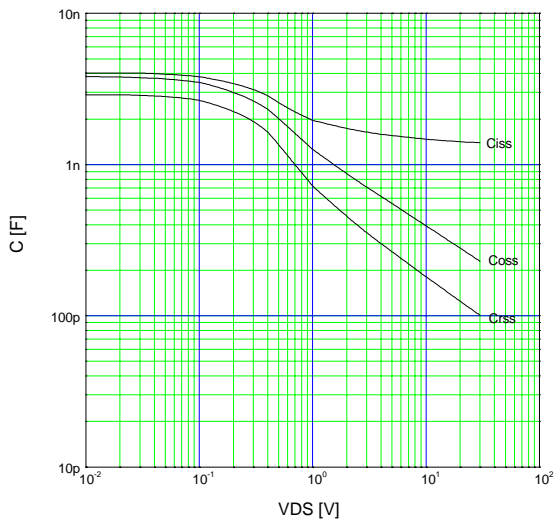
Typical forward transconductance  
 $g_{fs}=f(I_D)$ :80 $\mu$ s pulse test,  $V_{DS}=25\text{V}$ ,  $T_{ch}=25^\circ\text{C}$



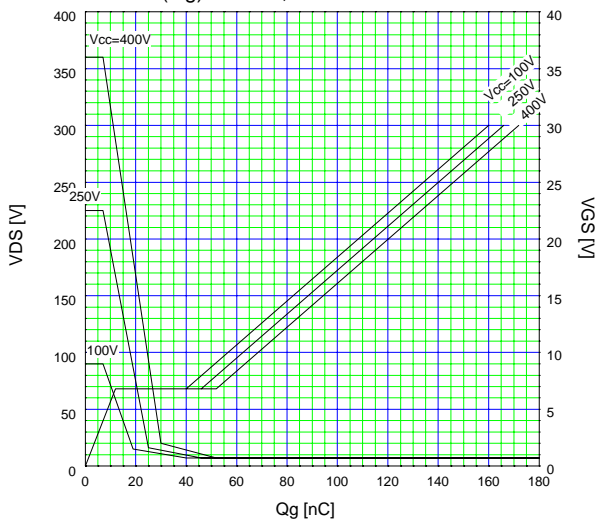
Gate threshold voltage  
 $V_{GS(th)}=f(T_{ch})$ : $I_D=1\text{mA}$ ,  $V_{DS}=V_{GS}$



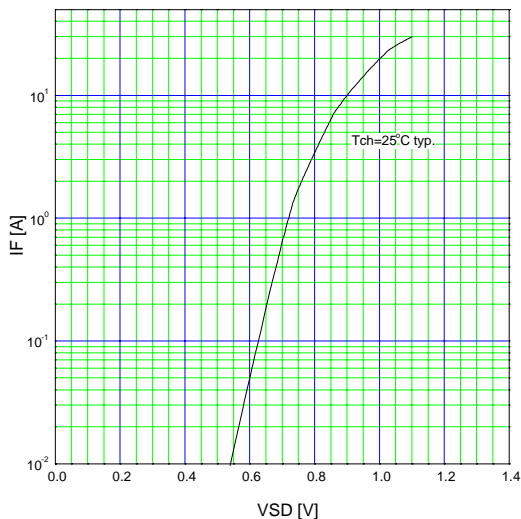
Typical capacitances  
 $C=f(V_{DS}): V_{GS}=0V, f=1MHz$



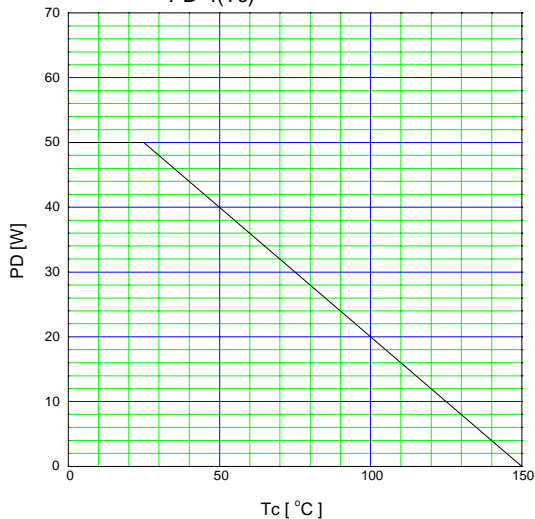
Typical gate charge characteristic  
 $V_{GS}=f(Q_g): I_D=15A, T_c=25^\circ C$



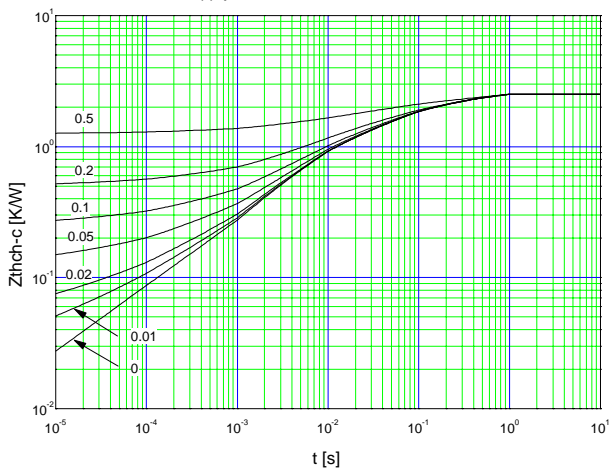
Forward characteristic of reverse of diode  
 $I_F=f(V_{SD}): 80\mu s \text{ pules test}, V_{GS}=0V$



Power Dissipation  
 $PD=f(T_c)$



Transient thermal impedance  
 $Z_{thc-c}=f(t)$  parameter:  $D=t/T$



Safe operating area  
 $I_D=f(V_{DS}): D=0.01, T_c=25^\circ C$

